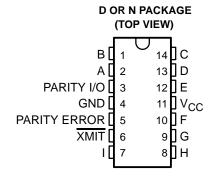
- Generates Either Odd or Even Parity for Nine Data Lines
- Cascadable for n-Bits Parity
- Direct Bus Connection for Parity Generation or for Checking by Using the Parity I/O Port
- Flow-Through Architecture Optimizes
 PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs



description

The 74AC11286 universal 9-bit parity generator/checker features a local output for parity checking and a bus-driving parity I/O port for parity generation/checking. The word-length capability is easily expanded by cascading.

The XMIT control input is implemented specifically to accommodate cascading. When the XMIT is low, the parity tree is disabled and the PARITY ERROR output will remain at a high logic level regardless of the input levels. When XMIT is high, the parity tree is enabled. The PARITY ERROR output will indicate a parity error when either an even number of inputs (A through I) are high and PARITY I/O is forced to a low logic level, or when an odd number of inputs are high and PARITY I/O is forced to a high logic level.

The I/O control circuitry was designed so that the I/O port will remain in the high-impedance state during power up or power down to prevent bus glitches.

The 74AC11286 is characterized for operation from -40° C to 85°C.

FUNCTION TABLE

NUMBER OF INPUTS (A THRU I) THAT ARE HIGH	XMIT INPUT	PARITY I/O	PARITY ERROR OUTPUT
0, 2, 4, 6, 8	I	Н	Н
1, 3, 5, 7, 9	1	L	Н
0.0.4.0.0	h	h	Н
0, 2, 4, 6, 8	h	Ι	L
12570	h	h	Ĺ
1, 3, 5, 7, 9	h	I	Н

h — high input level

I — low input level

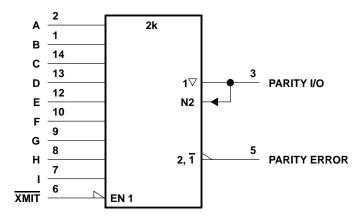
H — high output level

L — low output level

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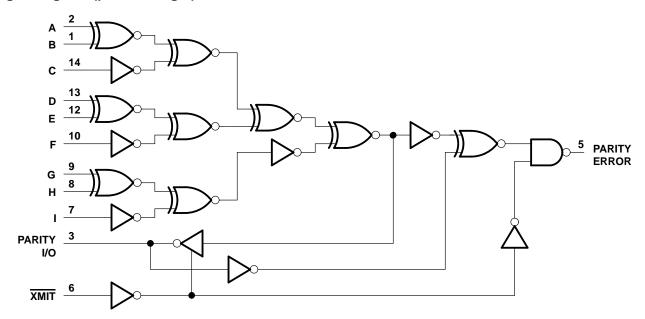


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	± 50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	± 50 mA
Continuous current through V _{CC} or GND	± 100 mA
Storage temperature range	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		3		5.5	V
		V _{CC} = 3 V	2.1			
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			V
		$V_{CC} = 5.5 \text{ V}$	3.85			
		V _{CC} = 3 V			0.9	
V_{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$		1.35	V	
		$V_{CC} = 5.5 \text{ V}$			1.65	
٧ _I	Input voltage		0		VCC	V
٧o	Output voltage		0		VCC	V
		V _{CC} = 3 V		- 4	_	
ЮН	High-level output current	$V_{CC} = 4.5 \text{ V}$			- 24	mA
		$V_{CC} = 5.5 \text{ V}$			-24	
		V _{CC} = 3 V			12	
lOL	Low-level output current	$V_{CC} = 4.5 \text{ V}$			24	mA
		$V_{CC} = 5.5 \text{ V}$			24	
Δt/Δν	Input transition rise or fall rate		0		10	ns/V
TA	Operating free-air temperature		- 40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	W	T _A = 25°C			BAINI	MAY	LIMIT
PARAMETER		Vcc	MIN	TYP	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		
	I _{OH} = - 50 μA	4.5 V	4.4			4.4		
		5.5 V	5.5 V 5.4 5	5.4				
VOH	I _{OH} = – 4 mA	3 V	2.58			2.48		
		4.5 V	3.94			3.8		
	I _{OH} = – 24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V	5.5 V 0.1		0.1			
V_{OL}	I _{OL} = 12 mA	3 V			0.36		0.44	-
		4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V			0.36		0.44	1
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	1
loz	$V_O = V_{CC}$ or GND	5.5 V			± 0.5		± 5	μA
lį	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΔ
Ci	V _I = V _{CC} or GND	5 V		3.5				pF
Со	V _O = V _{CC} or GND	5 V		8.5				рF

T Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



74AC11286 9-BIT PARITY GENERATOR/CHECKER WITH BUS DRIVER PARITY I/O PORTS

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V, (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ТО	T,	Վ = 25°C	;	MIN	MAX	UNIT
FARAWIETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	UNIT
t _{PLH}	Any A thru I	PARITY I/O	2.6	10	11.7	2.6	13.1	ns
^t PHL		FARIT I/O	3.8	11.6	14.5	3.8	16.1	115
^t PLH	Any A thru I	PARITY ERROR	3	8.5	13.1	3	14.7	ns
t _{PHL}	Ally A tillu I	PARITI ERROR	4	10.9	16	4	17.8	ns
tPLH	PARITY I/O	PARITY ERROR	2.2	5.9	7.6	2.2	8.4	ns
t _{PHL}	PARITTI/O	PARITI ERROR	3.4	7.9	10.2	3.4	11.1	110
^t PZH	XMIT	PARITY I/O	1.8	4.9	6.4	1.8	7	ns
t _{PZL}	AMIT	FARIT I/O	3.5	9.7	12.8	3.5	13.6	115
^t PHZ		PARITY I/O	3.2	5.4	6.6	3.2	7	ns
t _{PLZ}	XMIT	I AKIT I/O	3.2	5.4	6.7	3.2	7.2	110

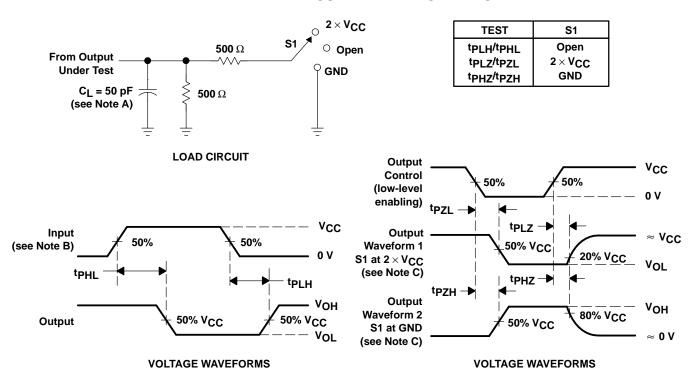
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V, (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т,	գ = 25°C	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	UNIT
^t PLH	Any A thru I	PARITY I/O	2	5.5	8	2	9	ns
^t PHL		FARITI/O	3.1	6.9	9.1	3.1	10.7	115
^t PLH	Any A thru I	PARITY ERROR	2.5	5.2	8.9	2.5	10	ns
^t PHL		FARITI ERROR	3.3	6.5	10.7	3.3	12	115
^t PLH	PARITY I/O	PARITY ERROR	1.9	3.9	5.6	1.9	6.2	ns
^t PHL		FARITI ERROR	2.9	5	7.2	2.9	7.9	115
^t PZH	XMIT	PARITY I/O	1.4	3.3	4.9	1.4	5.3	ns
^t PZL	AMIT	TAKIT I/O	3	5.4	8.3	3	8.9	115
^t PHZ	XMIT	PARITY I/O	3.1	4.8	6.1	3.1	6.5	ns
[†] PLZ	AIVII I	TAKITI I/O	3	4.6	6	3	6.3	113

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT	
C _{pd} Power dissipation capacitance	Outputs enabled	C _I = 50 pF, f = 1 MHz	53	pF	
Cpd	Power dissipation capacitance	Outputs disabled	CL = 50 pr, 1 = 1 MHZ	46	pr

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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